Abstracts

Characterization of Microwave Integrated Circuits Using an Optical Phase-Locking and Sampling System

H.-L.A. Hung, M.G. Li, S.-L.L. Huang and C.H. Lee. "Characterization of Microwave Integrated Circuits Using an Optical Phase-Locking and Sampling System." 1991 MTT-S International Microwave Symposium Digest 91.2 (1991 Vol. II [MWSYM]): 507-510.

Using an optical technique, phase-locked microwave signals of up to 15 GHz from voltage-controlled oscillators (VCOs) have been achieved. Combining this technique with a photoconductive switch, a new microwave waveform sampling system that displays the characteristics of oscillators and amplifiers has been demonstrated. The approach has potential applications for optically phase-locked microwave subsystems and monolithic integrated circuit characterizations.

❑ Return to main document.